

# NEWS FROM THE ANALYTICAL INSTRUMENTATION FACILITY (AIF) - MAY 2021



### **AIF User Spotlight**

Samaher Salem is a final year doctoral student in the Forest Biomaterials department, coadvised by Drs. Lokendra Pal and Lucian Lucia. He and his research group have successfully developed bioplastics from modified cellulose nanofibrils, which have shown excellent barrier properties and biodegradability. Learn more about Samaher by clicking the link below.

Meet Samaher »



#### <u>We're Hiring Undergraduate Student Employees - Deadline is</u> <u>May 14</u>

The AIF is seeking to hire multiple undergraduate students as hourly employees. Students will work in the Analytical Instrumentation Facility (AIF) to primarily support one of the following laboratories: X-ray diffraction (XRD), surface analysis lab, X-ray computed tomography (CT) lab, or electron microscopy (EM) labs. To be considered for these positions, please submit a cover letter, resume, and unofficial transcript to aif-contact@ncsu.edu as soon as possible.

Apply Today »



## AIF's 50-in-50 Challenge

Are you interested in getting trained at the AIF? AIF's Director, Jacob Jones, committed AIF to training OVER 50 NEW INDEPENDENT LAB USERS in the next 50 days! Lab managers are being rewarded for their creativity in realizing this goal amidst the continuing health and safety constraints posed due to COVID. You can sign up by clicking the link below.

<u>Sign Up »</u>



# 13th Annual Triangle Soft Matter Workshop: May 17

NC State University is pleased to host the 13th Triangle Soft Matter Workshop on May 17, 2021 virtually. The half-day symposium focuses on interactions and collaborations among research groups in the Research Triangle working in the area of soft matter. It will include soundbites (i.e., two minute presentations by students/faculty) and poster sessions.

Register Here »

Primary Ion Beam Total Area Spect

### **ToF SIMS Introduction Seminar**

<u>Time-of-Flight Secondary Ion Mass Spectrometry (ToF SIMS) is a powerful analytical</u> <u>technique that can provide elemental and molecular information with high sensitivity from the</u> <u>sample surface to tens of microns into the sample. This seminar introduces users to the basics of</u> <u>ToF-SIMS. If you'd like to be trained or have any questions, please email Elaine Zhou at</u> <u>czhou@ncsu.edu.</u>

YouTube Video »

Sandia National Labs, Virginia Tech, Northwestern, and Stanford Are Hiring »